Notice of References Cited Application/Control No. 10/534,335 Examiner HENOK LEGESSE Applicant(s)/Patent Under Reexamination SAKUMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | Α | US-2002/0021312 A1 | 02-2002 | Matsumoto, Tadashi | 347/1 |
| * | В | US-2002/0018097 A1 | 02-2002 | Kitahara et al. | 347/42 |
| * | С | US-2003/0085978 A1 | 05-2003 | Ishii et al. | 347/104 |
| | D | US- | | | |
| | Е | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | Н | US- | | | |
| | ı | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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| | Ø | | | | | |
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| | Ø | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
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